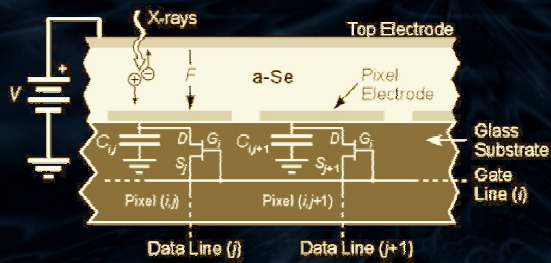


Selenium?

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Dose considerations for imaging detectors



Direct Imaging (absorption)

$$D_{skin} = \frac{2 \cdot L \cdot e^{-\mu \cdot L} \cdot SNR_{out}^2}{DQE(f) \cdot \mu^2 \cdot w^4 \cdot C_{\mu}^2} \cdot E_{\gamma} \cdot \left(\frac{\mu}{\rho} \right)$$

$$D_{sample} = \frac{\mu \cdot P \cdot h \cdot v}{DQE(f) \cdot \rho^2 \cdot w^4 \cdot \lambda^2 \cdot r_e^2}$$

Indirect imaging (scattering)

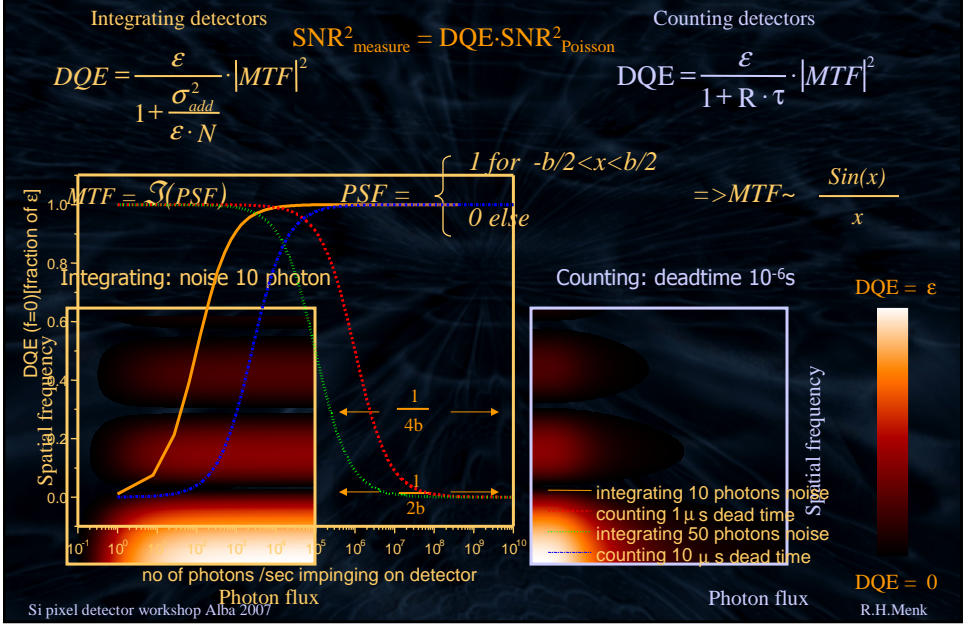
$$\approx \frac{1}{w^4 \cdot DQE(f)}$$

1 - DQE is what destroys the sample or patient and does not increase SNR

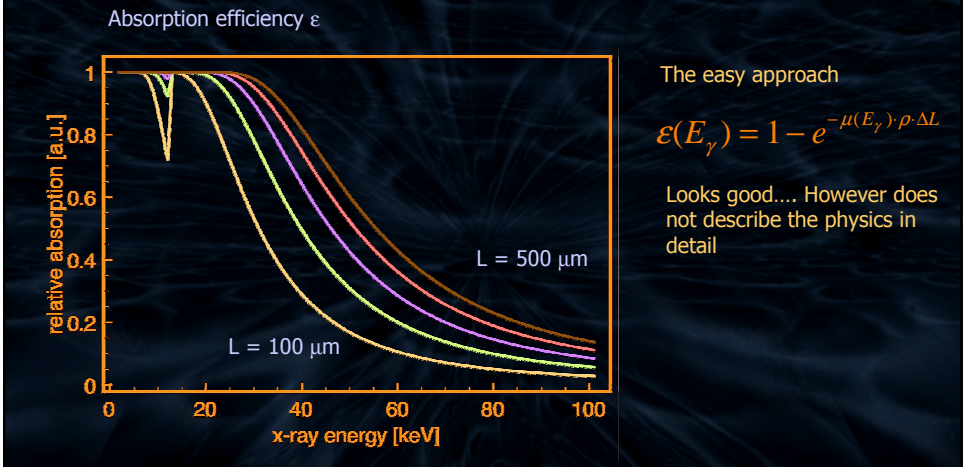
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Simple model of spatial frequency DQE



Why Selenium?



Drawbacks Selenium

$\varepsilon(E_\gamma) = 1 - e^{-\mu(E_\gamma) \cdot \rho \cdot \Delta L}$ Looks good.... However does not describe the physics in detail

More appropriate: Charge / energy efficiency

$$Q(E_\gamma) = \left(1 - e^{-\mu(E_\gamma) \cdot \rho \cdot \Delta L}\right) \underbrace{\eta(E_\gamma)}_{\text{energy efficiency}} \cdot \underbrace{\frac{E_\gamma \cdot e}{W_{ion}} \cdot \Gamma(E_{depletion})}_{\text{trapping / recombination}}$$

□ energy efficiency

□ trapping / recombination

$$\eta(E_\gamma) = \frac{\langle E_{dep} \rangle}{E_\gamma} = \frac{\int_0^\infty n(E_\gamma) \cdot E_\gamma \cdot dE_\gamma}{E_\gamma \cdot \int_0^\infty n(E_\gamma) \cdot dE_\gamma} \quad \Delta E_{dep} = \sqrt{\langle E_{dep}^2 \rangle - \langle E_{dep} \rangle^2}$$

$$\langle E_{dep}^2 \rangle = \frac{\int_0^\infty n(E_\gamma) \cdot E_\gamma^2 \cdot dE_\gamma}{\int_0^\infty n(E_\gamma) \cdot dE_\gamma} \Rightarrow \Delta Q^2 = \frac{\langle E_{dep} \rangle^2}{W_{ion}} \cdot e^2 \cdot \left(1 + \left(\frac{\Delta E_{dep}}{\langle E_{dep} \rangle}\right)^2\right)$$

Problem: W_{ion} depends from $E_{depletion}$

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More advanced model of spatial frequency DQE for a-Se

Integrating detectors

$$DQE = \frac{\varepsilon}{1 + \frac{\sigma_{add}^2}{\varepsilon \cdot N \cdot \left(1 + \left(\frac{\Delta E_{dep}}{\langle E_{dep} \rangle}\right)^2 \cdot \left(\frac{e \cdot E_\gamma}{W_{ion}}\right)^2\right)}} \cdot |MTF|^2$$

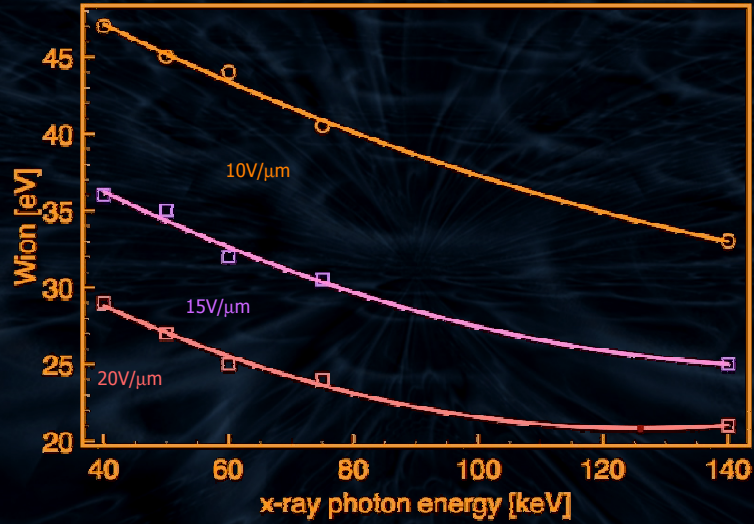
To understand the DQE one has to measure W_{ion}

$$W_{ion} = \frac{\varepsilon \cdot \eta(E_\gamma) \cdot e \cdot E_\gamma \cdot \Gamma(E_{depletion})}{Q}$$

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Measured W_{ion}

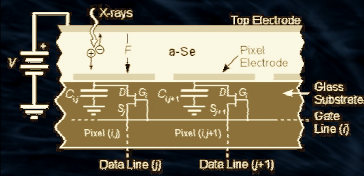


Stone et al.: X-ray sensitivity of amorphous selenium Medical Physics, Vol. 29, No. 3, March 2002

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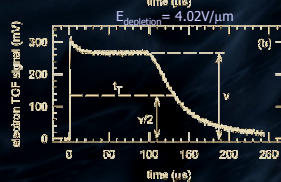
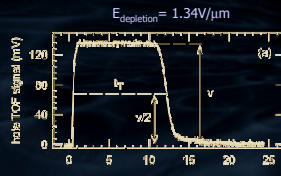
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TOF measurement for mobility, capture time and recombination



$$\delta = \frac{1}{\mu} < L \ll \mu^{\pm} \cdot \tau \cdot E_{depletion}$$

Absorption depth Thickness a-Se Schubweg



$L = 224\mu\text{m}$

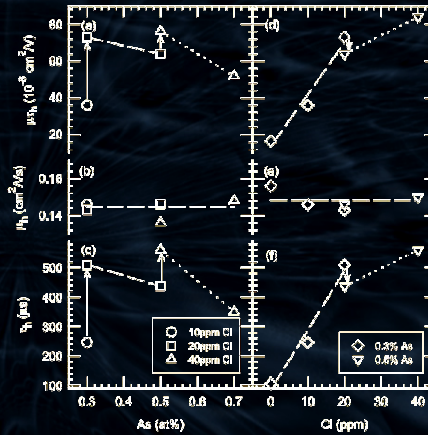
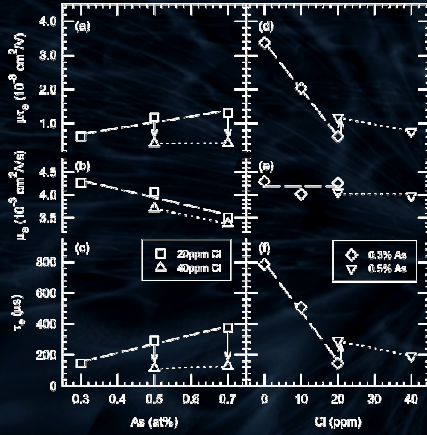
$$\mu^{\pm} = \frac{L^2}{V_{depletion} \cdot t_T}$$

$$\Gamma \approx \frac{e \cdot \mu}{t_T} = \frac{1}{N_2}$$

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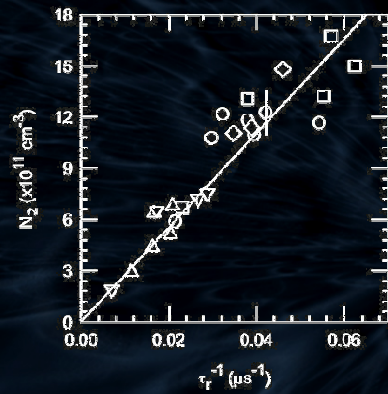
lifetime, mobility and range



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Trapped electron concentration



Trapped electron concentration in the a-Se bulk versus inverse hole recombination lifetime at different depth

$$C = \frac{1}{\tau_r \cdot N_2}$$

C Langevin recombination coefficient

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